

## AMENDMENTS TO THE SPECIFICATION

Please amend the paragraph beginning at line 13 on page 1 as follows:

The Joint ~~Action~~ Test Action Group (JTAG) was formed by manufacturers to address testing problems associated with smaller devices. The findings and recommendations of JTAG were used as the basis for the Institute of Electrical and Electronic Engineers (IEEE) Standard 1149.1, "Standard Test Access Port and Boundary-Scan Architecture." This standard is commonly referred to as JTAG. Boundary scan testing as defined by JTAG provides the ability to set and read values on device pins without direct physical access. According to JTAG, there are a number of registers associated with boundary scan testing. One of these registers is the Bypass register, which is a single-bit register that passes information from the "test data in" (TDI) to the "test data out" (TDO) pin. Devices under test can be coupled in series in what is referred to as a "scan chain." The Bypass register allows the testing of other devices in a scan chain without unnecessary overhead.